

## 30 A, 1200 V short circuit rugged IGBT with Ultrafast diode

### Features

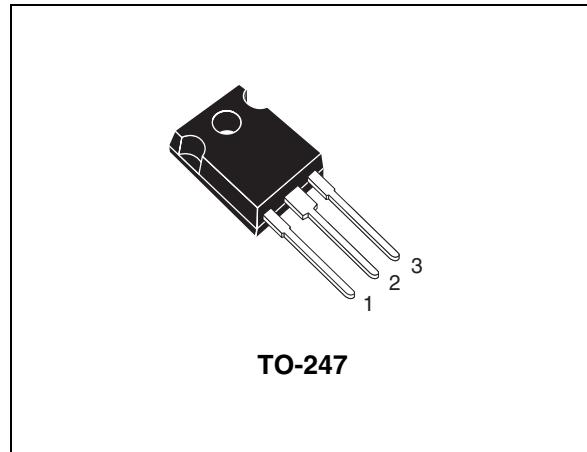
- Low on-losses
- High current capability
- Low gate charge
- Short circuit withstand time 10 µs
- IGBT co-packaged with Ultrafast free-wheeling diode

### Applications

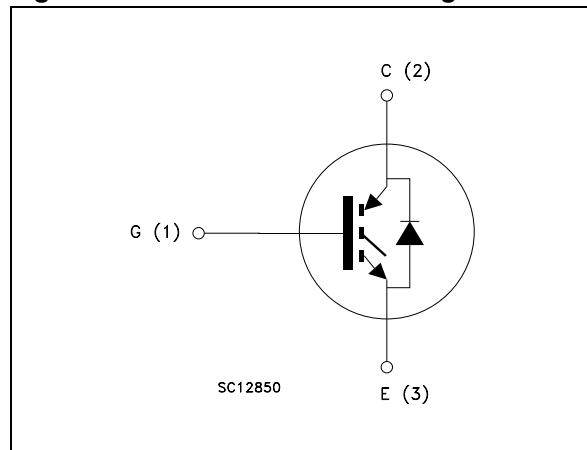
- Motor control

### Description

This high voltage and short-circuit rugged IGBT utilizes the advanced PowerMESH™ process resulting in an excellent trade-off between switching performance and low ON-state behavior.



**Figure 1. Internal schematic diagram**



**Table 1. Device summary**

| Order codes   | Markings    | Package           | Packaging |
|---------------|-------------|-------------------|-----------|
| STGW30N120KD  | GW30N120KD  | TO-247            | Tube      |
| STGWA30N120KD | GWA30N120KD | TO-247 long leads | Tube      |

## Contents

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# 1 Electrical ratings

**Table 2. Absolute maximum ratings**

| Symbol         | Parameter   | Value       | Unit |
|----------------|---|-------------|------|
| $V_{CES}$      | Collector-emitter voltage ( $V_{GE} = 0$ )  | 1200        | V    |
| $I_C^{(1)}$    | Collector current (continuous) at 25 °C   | 60          | A    |
| $I_C^{(1)}$    | Collector current (continuous) at 100 °C  | 30          | A    |
| $I_{CL}^{(2)}$ | Turn-off latching current   | 100         | A    |
| $I_{CP}^{(3)}$ | Pulsed collector current  | 100         | A    |
| $V_{GE}$       | Gate-emitter voltage  | ±25         | V    |
| $t_{SCW}$      | Short circuit withstand time, $V_{CE} = 0.5 V_{(BR)CES}$<br>$T_j = 125$ °C, $R_G = 10 \Omega$ , $V_{GE} = 12$ V | 10          | μs   |
| $P_{TOT}$      | Total dissipation at $T_C = 25$ °C  | 220         | W    |
| $I_F$          | Diode RMS forward current at $T_C = 25$ °C  | 30          | A    |
| $I_{FSM}$      | Surge non repetitive forward current $t_p = 10$ ms<br>sinusoidal  | 100         | A    |
| $T_j$          | Operating junction temperature  | – 55 to 125 | °C   |

1. Calculated according to the iterative formula:

$$I_C(T_C) = \frac{T_{j(max)} - T_C}{R_{thj-c} \times V_{CE(sat)(max)}(T_{j(max)}, I_C(T_C))}$$

2. Vclamp = 80% of  $V_{CES}$ ,  $T_j = 125$  °C,  $R_G = 10 \Omega$ ,  $V_{GE} = 15$  V  
 3. Pulse width limited by max. junction temperature allowed

**Table 3. Thermal resistance**

| Symbol         | Parameter                                     | Value | Unit |
|----------------|---|-------|------|
| $R_{thj-case}$ | Thermal resistance junction-case IGBT max.    | 0.45  | °C/W |
| $R_{thj-case}$ | Thermal resistance junction-case diode max.   | 1.6   | °C/W |
| $R_{thj-amb}$  | Thermal resistance junction-ambient IGBT max. | 50    | °C/W |

## 2 Electrical characteristics

$T_{CASE}=25\text{ }^{\circ}\text{C}$  unless otherwise specified.

**Table 4. Static**

| Symbol        | Parameter  | Test conditions   | Min. | Typ.       | Max.      | Unit                |
|---------------|--|---|------|------------|-----------|---------------------|
| $V_{(BR)CES}$ | Collector-emitter breakdown voltage ( $V_{GE} = 0$ ) | $I_C = 1\text{ mA}$   | 1200 |            |           | V                   |
| $V_{CE(sat)}$ | Collector-emitter saturation voltage                 | $V_{GE} = 15\text{ V}, I_C = 20\text{ A}$<br>$V_{GE} = 15\text{ V}, I_C = 20\text{ A}, T_c = 125\text{ }^{\circ}\text{C}$ |      | 2.8<br>2.7 | 3.85      | V                   |
| $V_{GE(th)}$  | Gate threshold voltage                               | $V_{CE} = V_{GE}, I_C = 1\text{ mA}$  | 4.5  |            | 6.5       | V                   |
| $I_{CES}$     | Collector cut-off current ( $V_{GE} = 0$ )           | $V_{CE} = 1200\text{ V}$<br>$V_{CE} = 1200\text{ V}, T_c = 125\text{ }^{\circ}\text{C}$                                   |      |            | 500<br>10 | $\mu\text{A}$<br>mA |
| $I_{GES}$     | Gate-emitter leakage current ( $V_{CE} = 0$ )        | $V_{GE} = \pm 20\text{ V}$  |      |            | $\pm 100$ | nA                  |
| $g_{fs}$      | Forward transconductance                             | $V_{CE} = 25\text{ V}, I_C = 20\text{ A}$   |      | 20         |           | S                   |

**Table 5. Dynamic**

| Symbol                              | Parameter   | Test conditions  | Min. | Typ.              | Max. | Unit           |
|-------------------------------------|---|--|------|-------------------|------|----------------|
| $C_{ies}$<br>$C_{oes}$<br>$C_{res}$ | Input capacitance<br>Output capacitance<br>Reverse transfer capacitance | $V_{CE} = 25\text{ V}, f = 1\text{ MHz}, V_{GE} = 0$             |      | 2520<br>170<br>33 |      | pF<br>pF<br>pF |
| $Q_g$<br>$Q_{ge}$<br>$Q_{gc}$       | Total gate charge<br>Gate-emitter charge<br>Gate-collector charge       | $V_{CE} = 960\text{ V}, I_C = 20\text{ A}, V_{GE} = 15\text{ V}$ |      | 105<br>21<br>56   |      | nC<br>nC<br>nC |

**Table 6. Switching on/off (inductive load)**

| Symbol  | Parameter   | Test conditions   | Min. | Typ.              | Max. | Unit                         |
|---|---|---|------|-------------------|------|------------------------------|
| $t_{d(on)}$<br>$t_r$<br>( $di/dt$ ) <sub>on</sub> | Turn-on delay time<br>Current rise time<br>Turn-on current slope  | $V_{CC} = 960 \text{ V}$ , $I_C = 20 \text{ A}$<br>$R_G = 10 \Omega$ , $V_{GE} = 15 \text{ V}$ ,<br>(see Figure 17)                           |      | 36<br>22<br>840   |      | ns<br>ns<br>A/ $\mu\text{s}$ |
| $t_{d(on)}$<br>$t_r$<br>( $di/dt$ ) <sub>on</sub> | Turn-on delay time<br>Current rise time<br>Turn-on current slope  | $V_{CC} = 960 \text{ V}$ , $I_C = 20 \text{ A}$<br>$R_G = 10 \Omega$ , $V_{GE} = 15 \text{ V}$ ,<br>$T_c = 125^\circ\text{C}$ (see Figure 17) |      | 35<br>22<br>760   |      | ns<br>ns<br>A/ $\mu\text{s}$ |
| $t_r(V_{off})$<br>$t_d(off)$<br>$t_f$             | Off voltage rise time<br>Turn-off delay time<br>Current fall time | $V_{CC} = 960 \text{ V}$ , $I_C = 20 \text{ A}$<br>$R_G = 10 \Omega$ , $V_{GE} = 15 \text{ V}$ ,<br>(see Figure 17)                           |      | 70<br>251<br>260  |      | ns<br>ns<br>ns               |
| $t_r(V_{off})$<br>$t_d(off)$<br>$t_f$             | Off voltage rise time<br>Turn-off delay time<br>Current fall time | $V_{CC} = 960 \text{ V}$ , $I_C = 20 \text{ A}$<br>$R_G = 10 \Omega$ , $V_{GE} = 15 \text{ V}$ ,<br>$T_c = 125^\circ\text{C}$ (see Figure 17) |      | 140<br>324<br>432 |      | ns<br>ns<br>ns               |

**Table 7. Switching energy (inductive load)**

| Symbol  | Parameter   | Test conditions   | Min. | Typ.              | Max. | Unit           |
|---|---|---|------|-------------------|------|----------------|
| $E_{on}^{(1)}$<br>$E_{off}^{(2)}$<br>$E_{ts}$ | Turn-on switching losses<br>Turn-off switching losses<br>Total switching losses | $V_{CC} = 960 \text{ V}$ , $I_C = 20 \text{ A}$<br>$R_G = 10 \Omega$ , $V_{GE} = 15 \text{ V}$ ,<br>(see Figure 17)                           |      | 2.4<br>4.3<br>6.7 |      | mJ<br>mJ<br>mJ |
| $E_{on}^{(1)}$<br>$E_{off}^{(2)}$<br>$E_{ts}$ | Turn-on switching losses<br>Turn-off switching losses<br>Total switching losses | $V_{CC} = 960 \text{ V}$ , $I_C = 20 \text{ A}$<br>$R_G = 10 \Omega$ , $V_{GE} = 15 \text{ V}$ ,<br>$T_c = 125^\circ\text{C}$ (see Figure 17) |      | 3.9<br>5.8<br>9.7 |      | mJ<br>mJ<br>mJ |

1.  $E_{on}$  is the turn-on losses when a typical diode is used in the test circuit in Figure 17. If the IGBT is offered in a package with a co-pack diode, the co-pack diode is used as external diode. IGBTs and diode are at the same temperature ( $25^\circ\text{C}$  and  $125^\circ\text{C}$ )
2. Turn-off losses include also the tail of the collector current

**Table 8. Collector-emitter diode**

| Symbol                            | Parameter  | Test conditions  | Min. | Typ.             | Max. | Unit          |
|-----------------------------------|--|--|------|------------------|------|---------------|
| $V_F$                             | Forward on-voltage   | $I_F = 20 \text{ A}$<br>$I_F = 20 \text{ A}$ , $T_c = 125^\circ\text{C}$   |      | 1.9<br>1.7       |      | V<br>V        |
| $t_{rr}$<br>$Q_{rr}$<br>$I_{rrm}$ | Reverse recovery time<br>Reverse recovery charge<br>Reverse recovery current | $I_F = 20 \text{ A}$ , $V_R = 45 \text{ V}$ ,<br>$di/dt = 100 \text{ A}/\mu\text{s}$<br>(see Figure 20)                                |      | 84<br>235<br>5.6 |      | ns<br>nC<br>A |
| $t_{rr}$<br>$Q_{rr}$<br>$I_{rrm}$ | Reverse recovery time<br>Reverse recovery charge<br>Reverse recovery current | $I_F = 20 \text{ A}$ , $V_R = 45 \text{ V}$ ,<br>$T_c = 125^\circ\text{C}$ ,<br>$di/dt = 100 \text{ A}/\mu\text{s}$<br>(see Figure 20) |      | 152<br>722<br>9  |      | ns<br>nC<br>A |

## 2.1 Electrical characteristics (curves)

Figure 2. Output characteristics

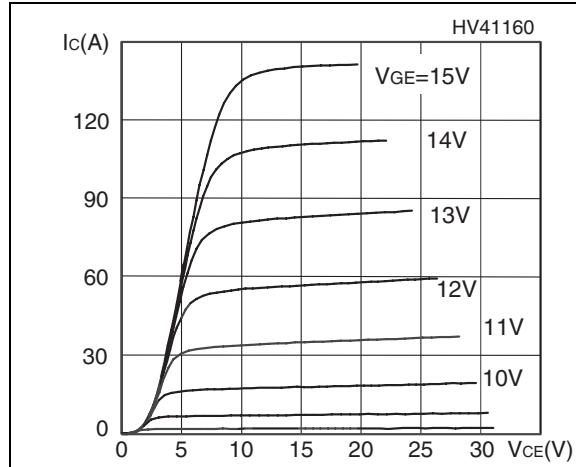


Figure 3. Transfer characteristics

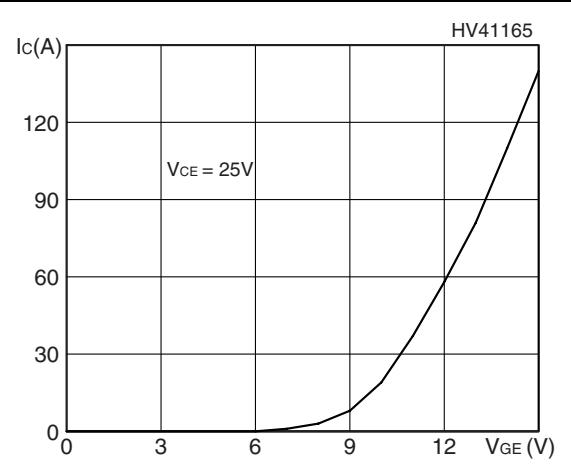


Figure 4. Transconductance

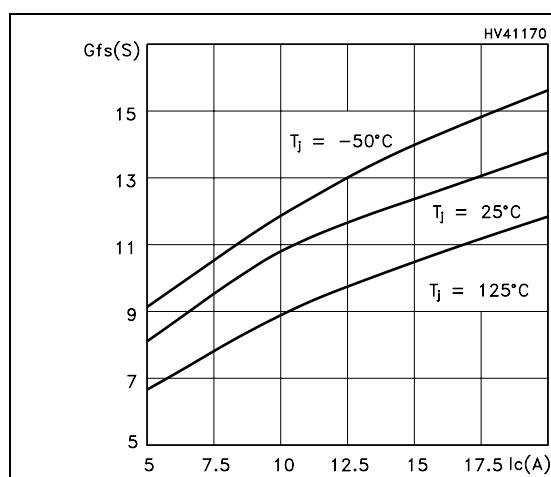


Figure 5. Collector-emitter on voltage vs. temperature

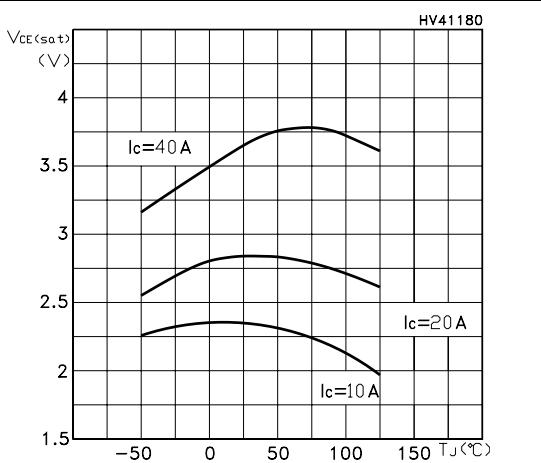


Figure 6. Gate charge vs. gate-source voltage

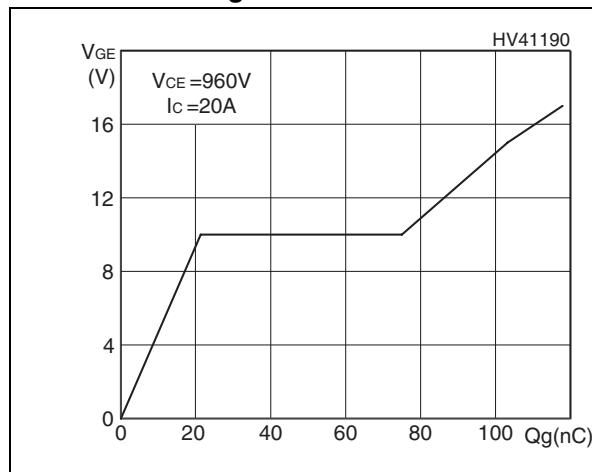
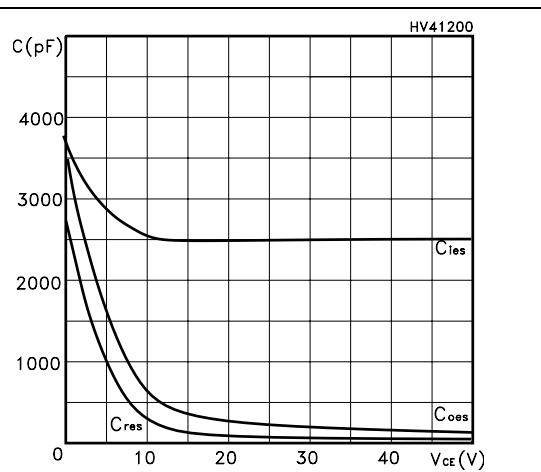
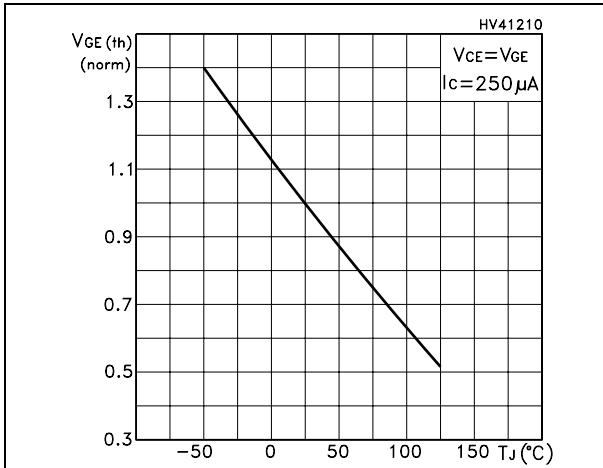
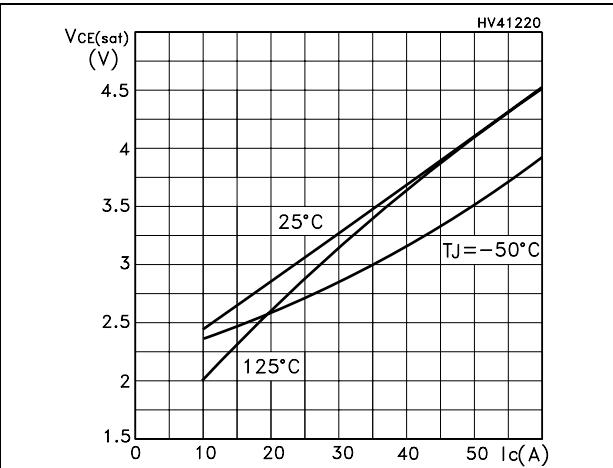
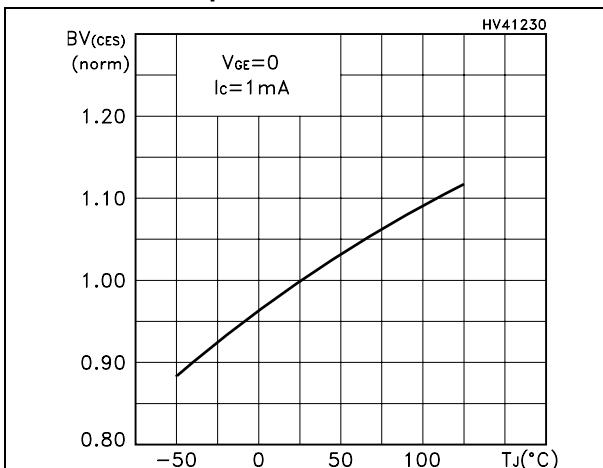
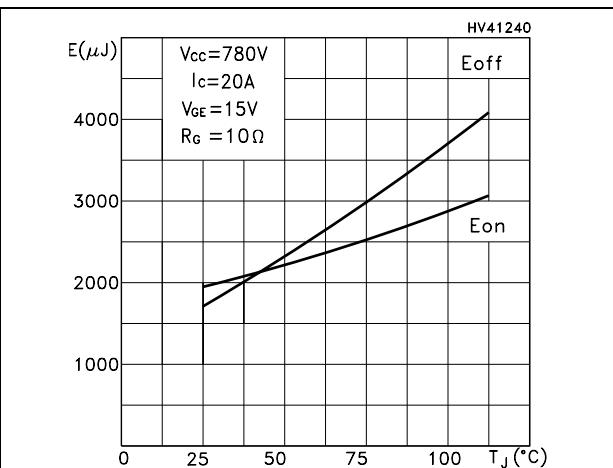
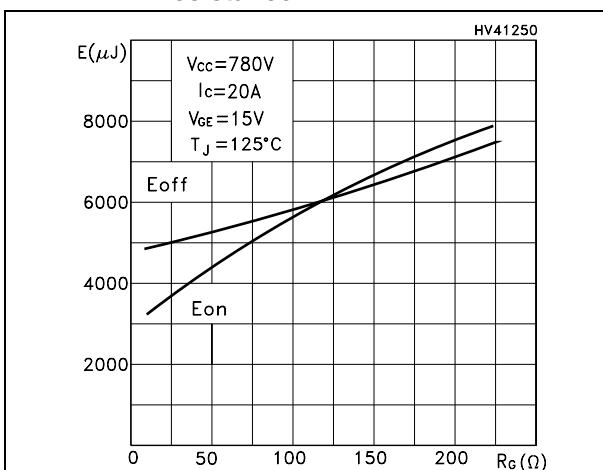
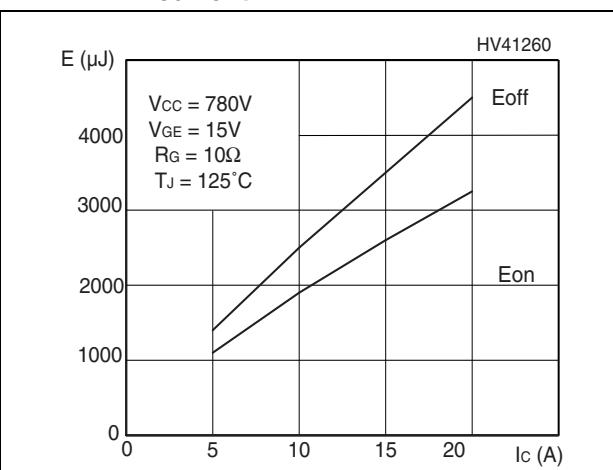
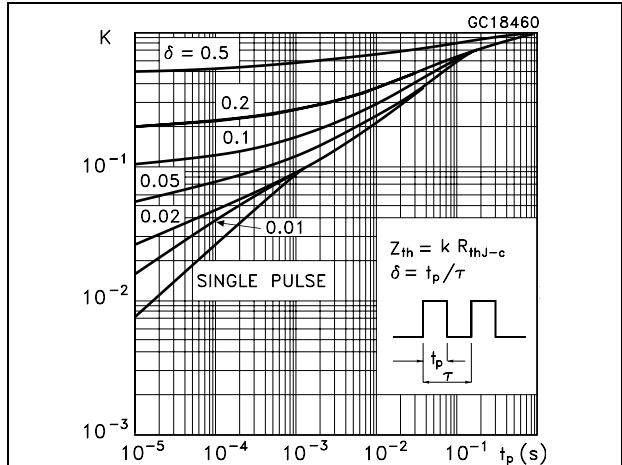
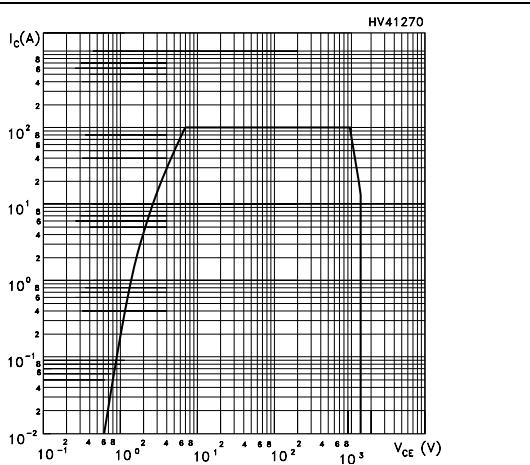
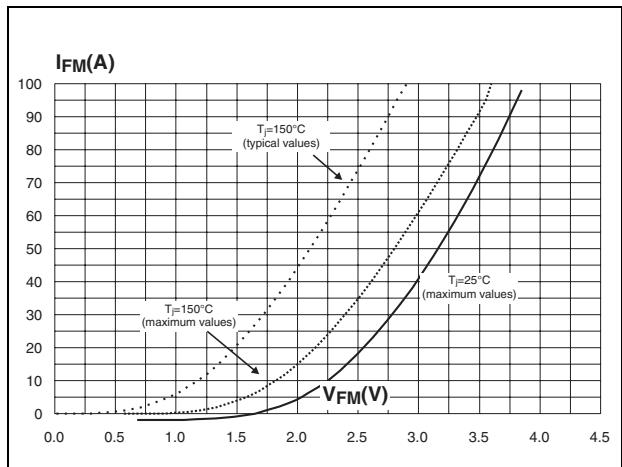


Figure 7. Capacitance variations

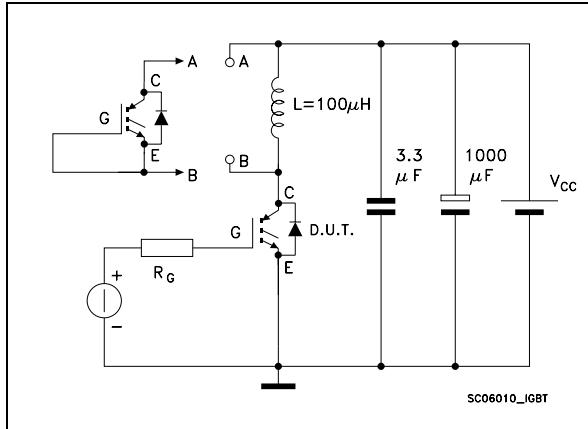


**Figure 8. Normalized gate threshold voltage vs. temperature****Figure 9. Collector-emitter on voltage vs. collector current****Figure 10. Normalized breakdown voltage vs. temperature****Figure 11. Switching losses vs. temperature****Figure 12. Switching losses vs. gate resistance****Figure 13. Switching losses vs. collector current**

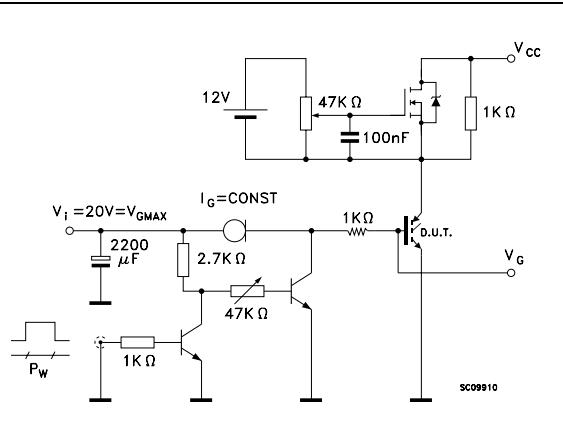
**Figure 14. Thermal impedance****Figure 15. Turn-off SOA****Figure 16. Forward voltage drop vs. forward current**

### 3 Test circuit

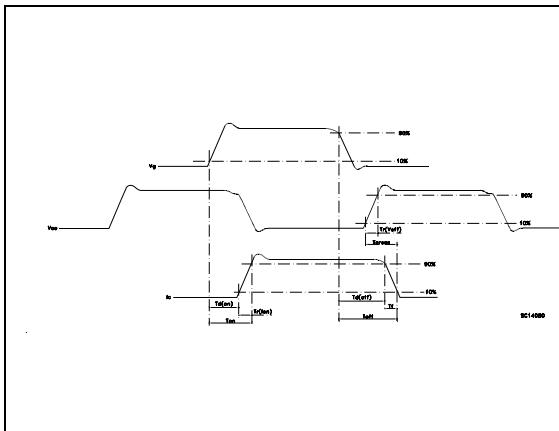
**Figure 17. Test circuit for inductive load switching**



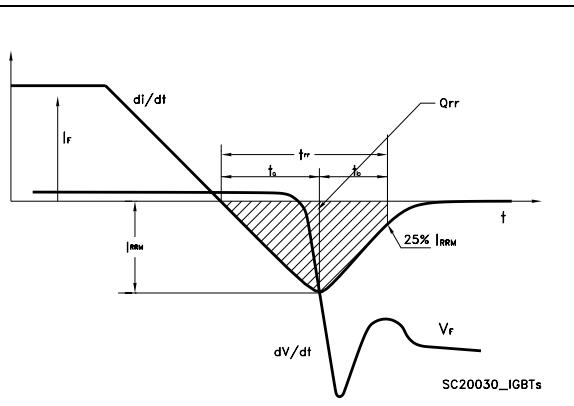
**Figure 18. Gate charge test circuit**



**Figure 19. Switching waveform**



**Figure 20. Diode recovery time waveform**



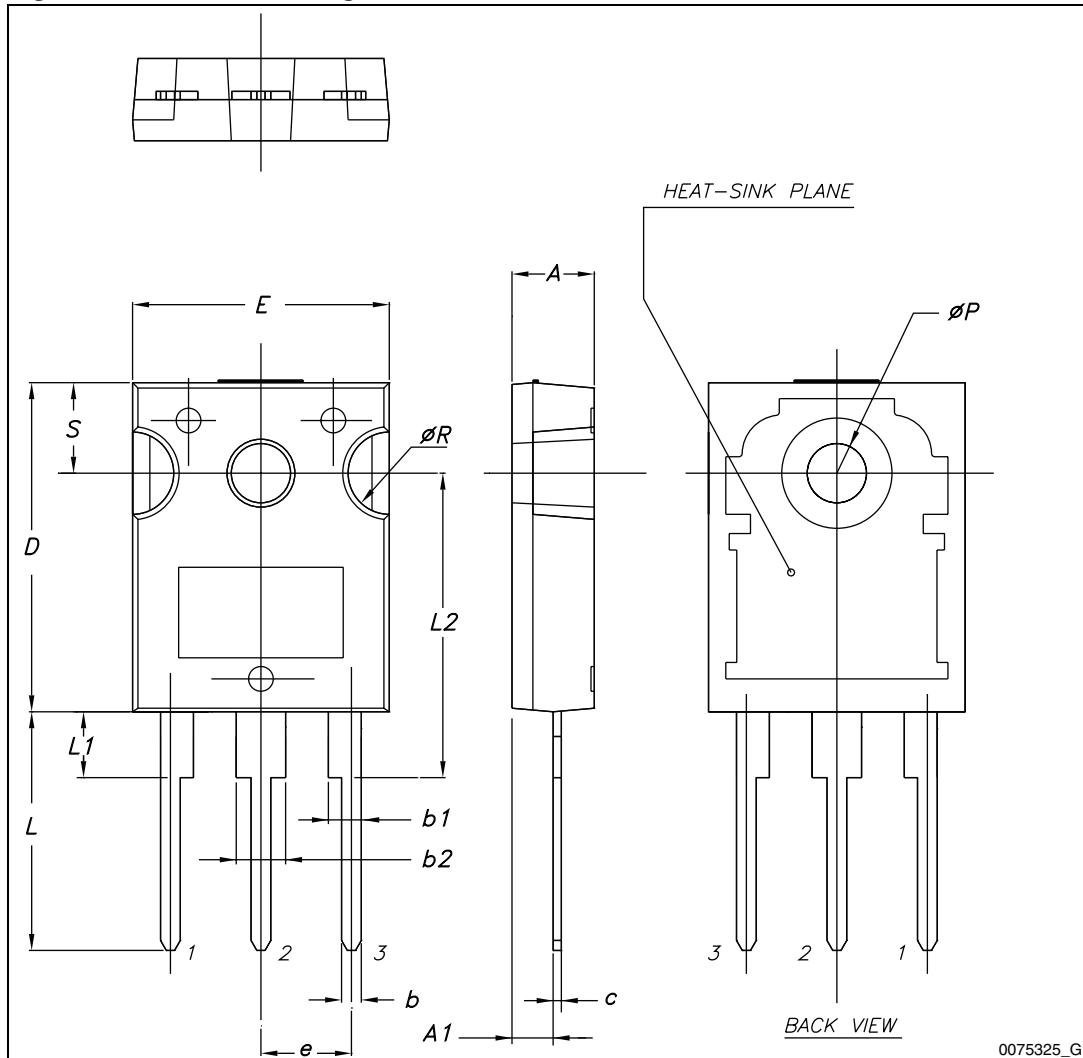
## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com).  
ECOPACK® is an ST trademark.

**Table 9. TO-247 mechanical data**

| Dim. | mm.   |       |       |
|------|-------|-------|-------|
|      | Min.  | Typ.  | Max.  |
| A    | 4.85  |       | 5.15  |
| A1   | 2.20  |       | 2.60  |
| b    | 1.0   |       | 1.40  |
| b1   | 2.0   |       | 2.40  |
| b2   | 3.0   |       | 3.40  |
| c    | 0.40  |       | 0.80  |
| D    | 19.85 |       | 20.15 |
| E    | 15.45 |       | 15.75 |
| e    | 5.30  | 5.45  | 5.60  |
| L    | 14.20 |       | 14.80 |
| L1   | 3.70  |       | 4.30  |
| L2   |       | 18.50 |       |
| ØP   | 3.55  |       | 3.65  |
| ØR   | 4.50  |       | 5.50  |
| S    | 5.30  | 5.50  | 5.70  |

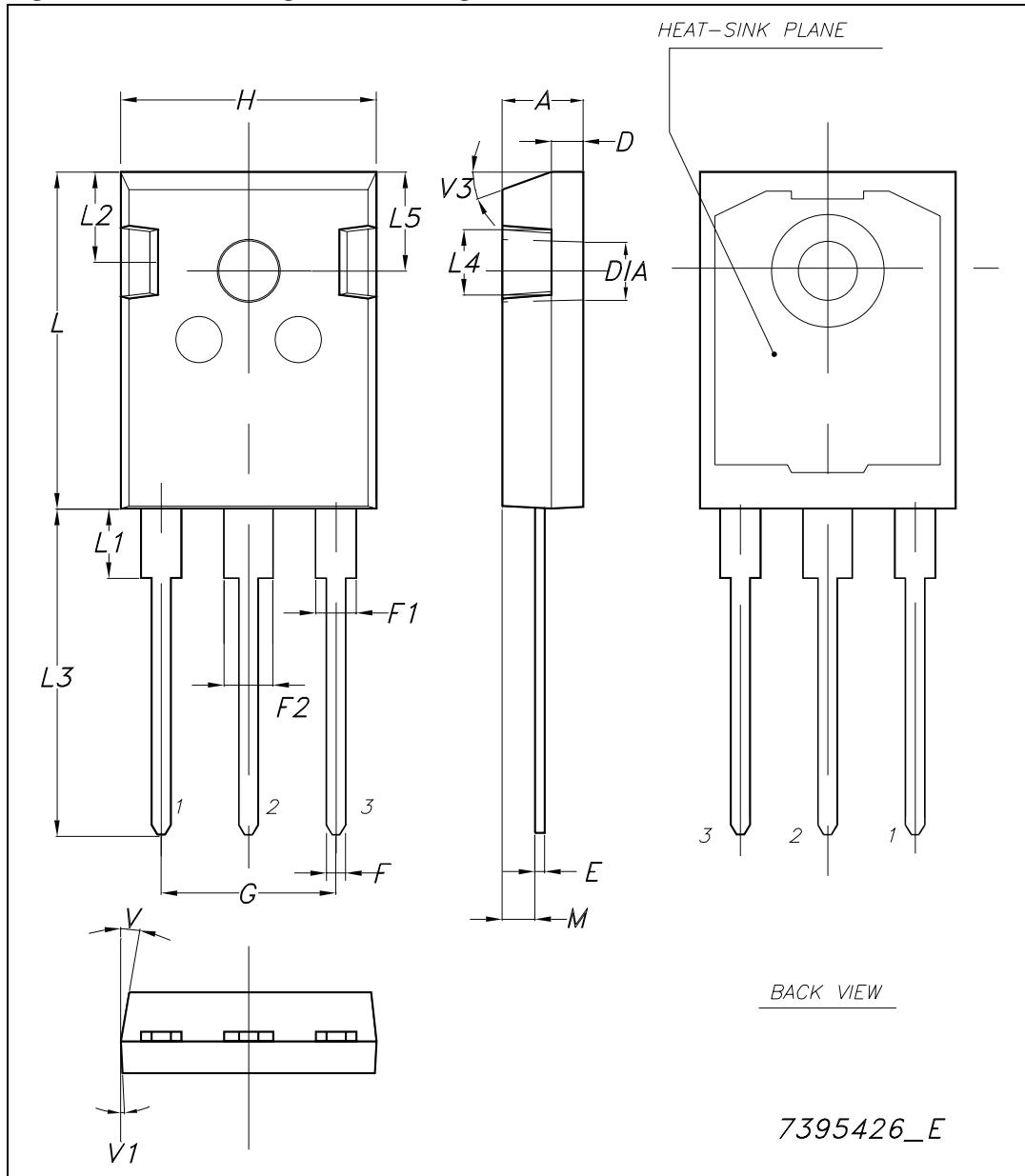
Figure 21. TO-247 drawing dimensions



**Table 10.** TO-247 long leads mechanical data

| Dim. | mm        |      |       |
|------|-----------|------|-------|
|      | Min.      | Typ. | Max.  |
| A    | 4.90      |      | 5.15  |
| D    | 1.85      |      | 2.10  |
| E    | 0.55      |      | 0.67  |
| F    | 1.07      |      | 1.32  |
| F1   | 1.90      |      | 2.38  |
| F2   | 2.87      |      | 3.38  |
| G    | 10.90 BSC |      |       |
| H    | 15.77     |      | 16.02 |
| L    | 20.82     |      | 21.07 |
| L1   | 4.16      |      | 4.47  |
| L2   | 5.49      |      | 5.74  |
| L3   | 20.05     |      | 20.30 |
| L4   | 3.68      |      | 3.93  |
| L5   | 6.04      |      | 6.29  |
| M    | 2.27      |      | 2.52  |
| V    |           | 10°  |       |
| V1   |           | 3°   |       |
| V3   |           | 20°  |       |
| Dia. | 3.55      |      | 3.66  |

Figure 22. TO-247 long leads drawing



## 5 Revision history

**Table 11. Document revision history**

| Date        | Revision | Changes   |
|-------------|----------|---|
| 29-Jan-2008 | 1        | Initial release   |
| 18-Jun-2008 | 2        | Update values in <a href="#">Table 2</a>  |
| 02-Dec-2008 | 3        | Update $P_{TOT}$ and $R_{thj-case}$ value (see <a href="#">Table 2</a> and <a href="#">Table 3</a> )  |
| 17-Jan-2012 | 4        | Added order code STGWA30N120KD <a href="#">Table 1 on page 1</a> ,<br>mechanical data TO-247 long leads <a href="#">Table 10 on page 12</a> and<br><a href="#">Figure 22 on page 13</a> . |
| 27-Feb-2012 | 5        | Modified: <a href="#">Description on page 1</a> .   |

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